

SMALL SIGNAL SCHOTTKY DIODES

DESCRIPTION

General purpose metal to silicon diodes featuring very low turn-on voltage fast switching.

These devices have integrated protection against excessive voltage such as electrostatic discharges.


MINIMELF
 (Glass)

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	30	V
I_F	Forward Continuous Current	200	mA
I_{FRM}	Repetitive Peak Forward Current $t_p \leq 1\text{s}$ $\delta \leq 0.5$	500	mA
I_{FSM}	Surge non Repetitive Forward Current	4	A
P_{tot}	Power Dissipation	200	mW
T_{stg} T_j	Storage and Junction Temperature Range	- 65 to 150 - 65 to 125	°C °C
T_L	Maximum Temperature for Soldering during 15s	260	°C

THERMAL RESISTANCE

Symbol	Parameter	Value	Unit
$R_{th(j-l)}$	Junction-leads	300	°C/W

ELECTRICAL CHARACTERISTICS

STATIC CHARACTERISTICS

Symbol	Test Conditions			Min.	Typ.	Max.	Unit
V _(BR)	T _j = 25°C	I _R = 100µA				30	V
V _F *	T _j = 25°C	I _F = 200mA	All Types			1	V
	T _j = 25°C	I _F = 10mA	BAT 42			0.4	
	T _j = 25°C	I _F = 50mA				0.65	
	T _j = 25°C	I _F = 2mA	BAT 43	0.26	0.33		µA
	T _j = 25°C	I _F = 15mA				0.45	
I _R *	T _j = 25°C		V _R = 25V			0.5	µA
	T _j = 100°C					100	

DYNAMIC CHARACTERISTICS

Symbol	Test Conditions					Min.	Typ.	Max.	Unit
C	T _j = 25°C V _R = 1V f = 1MHz							7	pF
t _{rr}	T _j = 25°C I _F = 10mA I _R = 10mA i _{rr} = 1mA R _L = 100Ω							5	ns
η	T _j = 25°C R _L = 15KΩ C _L = 300pF f = 45MHz V _i = 2V					80			%

* Pulse test : t_p ≤ 300µs δ < 2%.

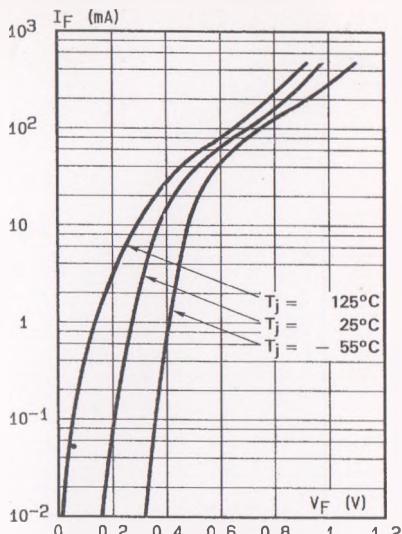


Fig.1 - Forward current versus forward voltage at different temperatures (typical values).

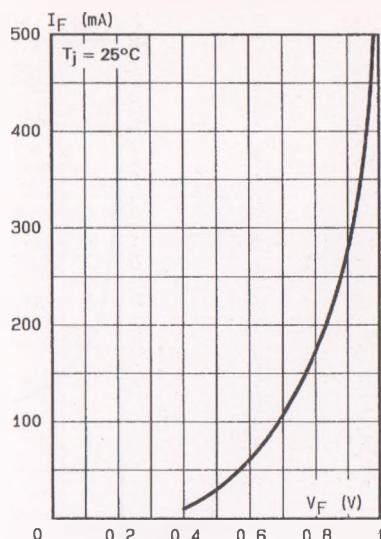


Fig.2 - Forward current versus forward voltage (typical values).

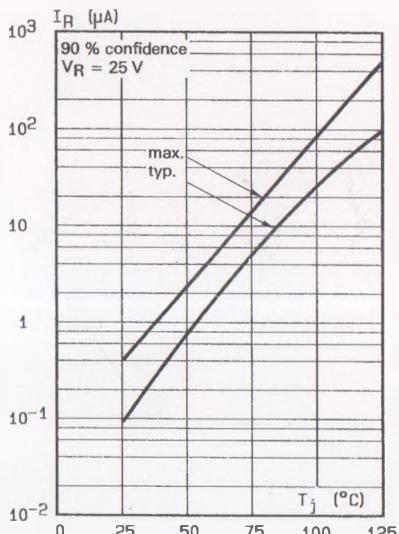


Fig.3 - Reverse current versus junction temperature.

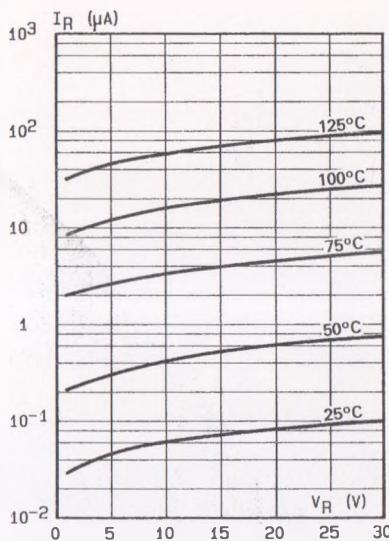


Fig.4 - Reverse current versus continuous reverse voltage (typical values).

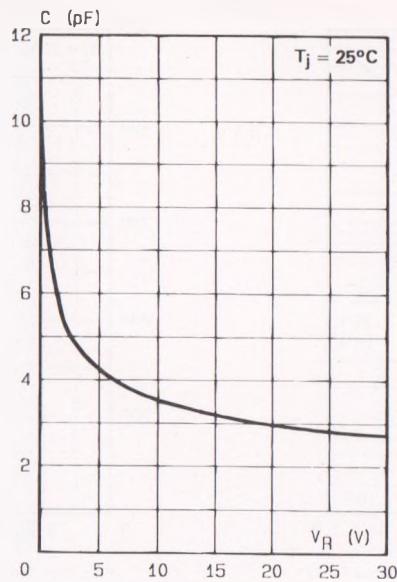


Fig.5 - Capacitance C versus
reverse applied voltage V_R
(typical values).